

Notice of References Cited

Application/Control No.

10/716,979

Applicant(s)/Patent Under
Reexamination
CHAN ET AL.

Examiner

John R. Hardee

Art Unit

1751

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,321,311	11-2001	Kim, Dae-Jung	711/157
	B	US-5,529,649	06-1996	Lund et al.	149/19.3
	C	US-5,468,313	11-1995	Wallace et al.	149/53
	D	US-4,916,206	04-1990	Day et al.	528/272
	E	US-6,613,168	09-2003	Reed et al.	149/19.5
	F	US-6,136,115	10-2000	Highsmith et al.	149/109.6
	G	US-5,962,803	10-1999	Guimont, John	86/21
	H	US-5,801,453	09-1998	Guimont, John	264/3.5
	I	US-6,652,682	11-2003	Fawls et al.	149/22
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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